

1 This listing of claims will replace all prior versions, and listings, of claims in the
2 application:

3
4 **Listing of Claims:**

5 1. A method comprising:

6 connecting the output of at least two driver circuits to a resistive network,
7 wherein the output signals from the at least two driver circuits are combined
8 through the resistive network to produce a resultant signal ; and

9 configuring the resistive network and the at least two driver circuits such
10 that the resultant signal is provided to a first node of the resistive network but not
11 to a second node of the resistive network.

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13 2. The method as recited in Claim 1, wherein the resultant signal
14 includes an attenuated version of at least one of the output signals.

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16 3. The method as recited in Claim 1, further comprising:

17 coupling an input/output node of an external circuit to the first node of the
18 resistive network, the external circuit being configured to receive the resultant
19 signal and output an external signal; and

20 coupling an input node of a receiver circuit to the second node of the
21 resistive network.

1 4. The method as recited in Claim 3, further comprising:
2 simultaneously providing the resultant signal to the external circuit and the
3 external signal to the receiver circuit, bi-directionally through a connector coupling
4 the resistive network to the external circuit.

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6 5. The method as recited in Claim 4, wherein the external circuit
7 includes a device under test (DUT).

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9 6. The method as recited in Claim 5, wherein the device under test
10 (DUT) includes an integrated circuit.

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12 7. The method as recited in Claim 4, wherein the at least two driver
13 circuits and the receiver circuit are part of an automated test equipment (ATE)
14 device.

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16 8. The method as recited in Claim 7, wherein the resistive network is
17 part of the automated test equipment (ATE) device.

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19 9. The method as recited in Claim 7, wherein the resistive network is
20 included in a load board coupled to the external circuit and the automated test
21 equipment (ATE) device.

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23 10-27. (Cancelled)